

Status of pixel chip simulation framework

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- Introduction
 - Context and goals of the activity
- Class-based SystemVerilog VE
 - Device Under Test (DUT)
 - Verification components
- UVM VE
 - Verification components
 - Evaluation of simulation performance
- Conclusion and future work

RD53 Collaboration (CMS/ATLAS)

Development of pixel readout integrated circuits for extreme rate and radiation

Verification working group (workpackage WG3):

Development of dedicated verification and simulation framework for optimization of next generation pixel chips

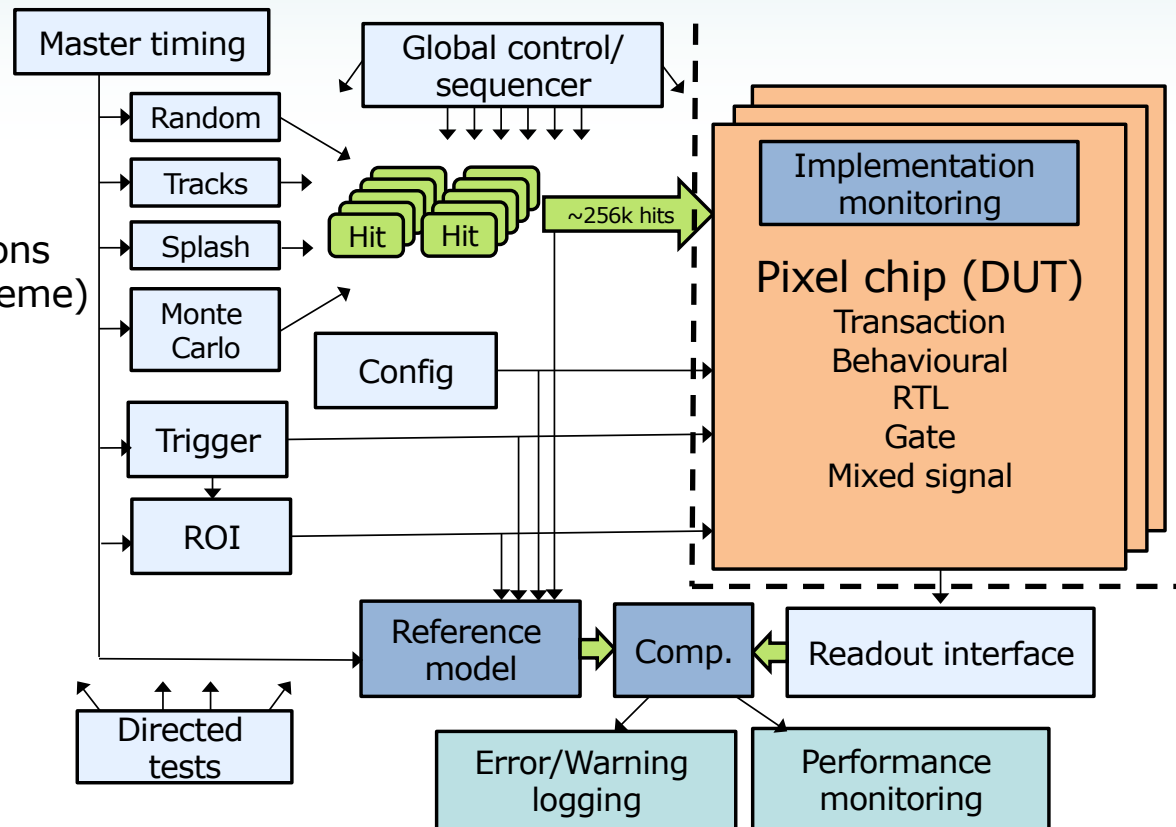
- **Goals:**

- Definition and evaluation of requirements for future pixel chips
- System performance evaluation for different pixel architectures
- Simulation of alternative pixel chip architectures at increasingly refined level as design progresses:
 - At both very high level and gate level
 - Specific IP to be plugged in the final design
- Pixel architecture optimization based on pixel grouping (storage logic shared)

→ Devoted simulation and verification framework

Proposed Verification Environment for RD53

- Very versatile and generic
- Different kinds of data sets
 - constrained random distributions to generate realistic (and extreme) pixel hits and triggers
 - particle hits from external Monte Carlo simulations and sensor simulations
 - mixed data
- Automated verification functions

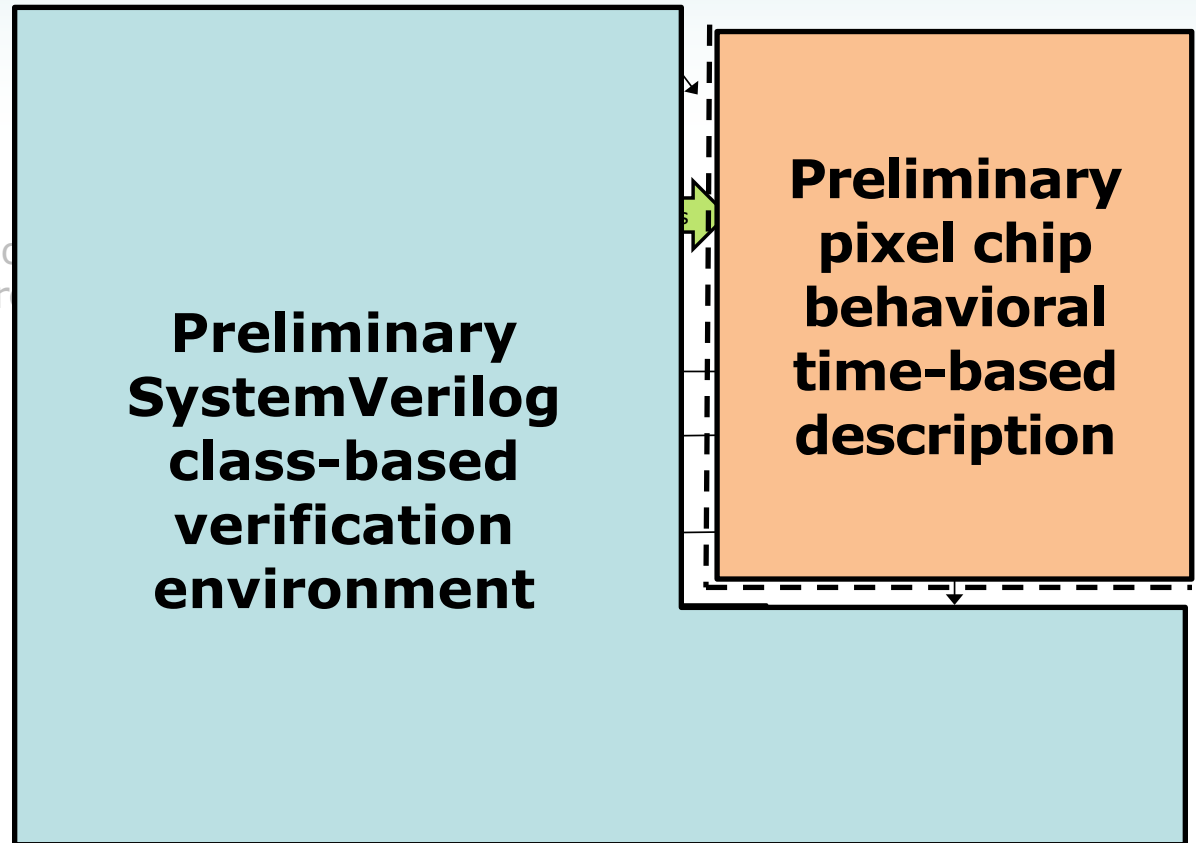


[J. Christiansen, M. Garcia-Sciveres, RD53 proposal, 2013]

- Hardware Verification and Description Language (HVDL): **SystemVerilog**
 - module-based Device Under Test (DUT) / class-based verification components
 - standardization, reusability → **Universal Verification Methodology (UVM)** library

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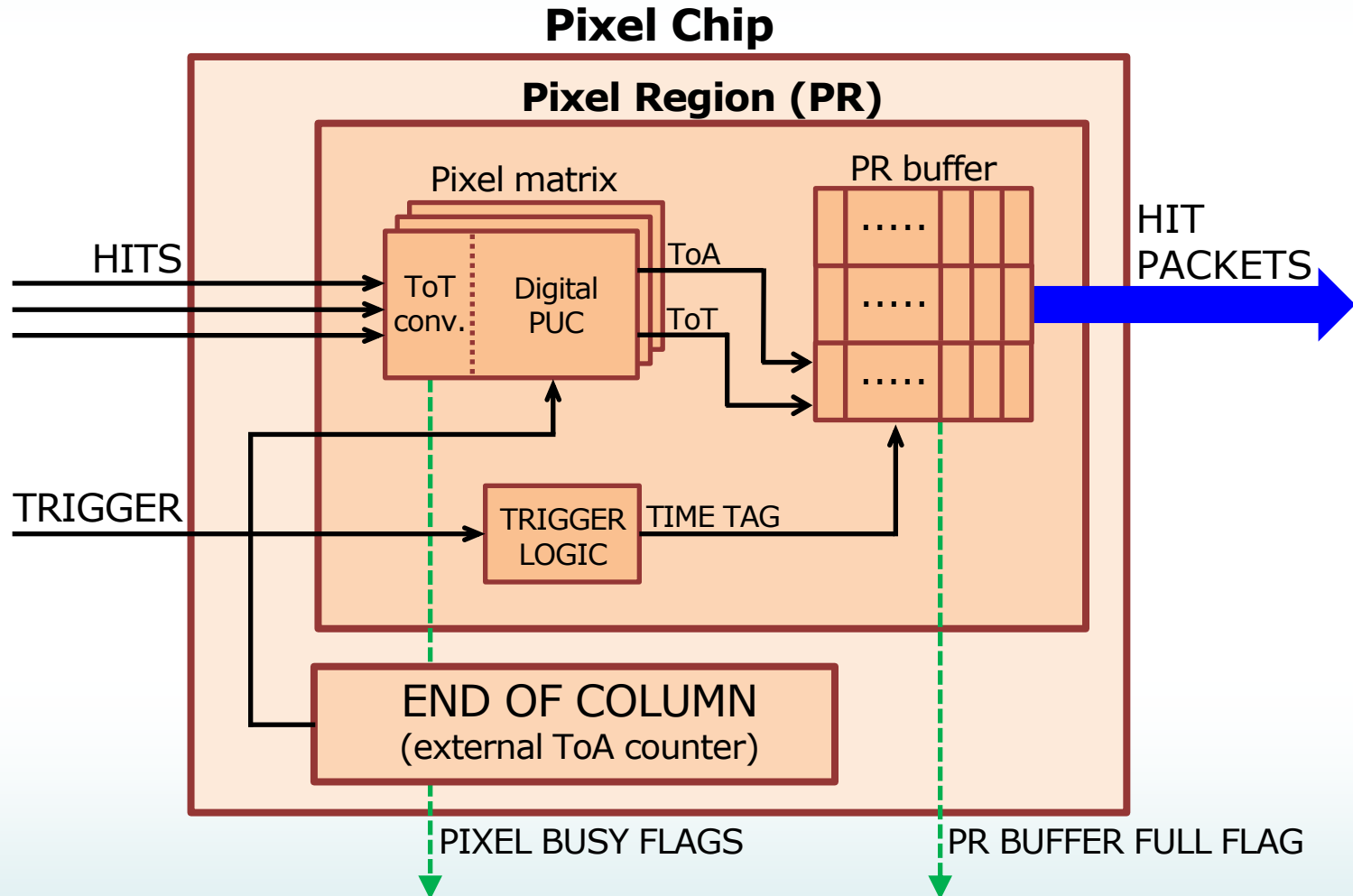


- Hardware Verilog
 - module-based
 - standardization

Software tool: *Cadence Incisive*

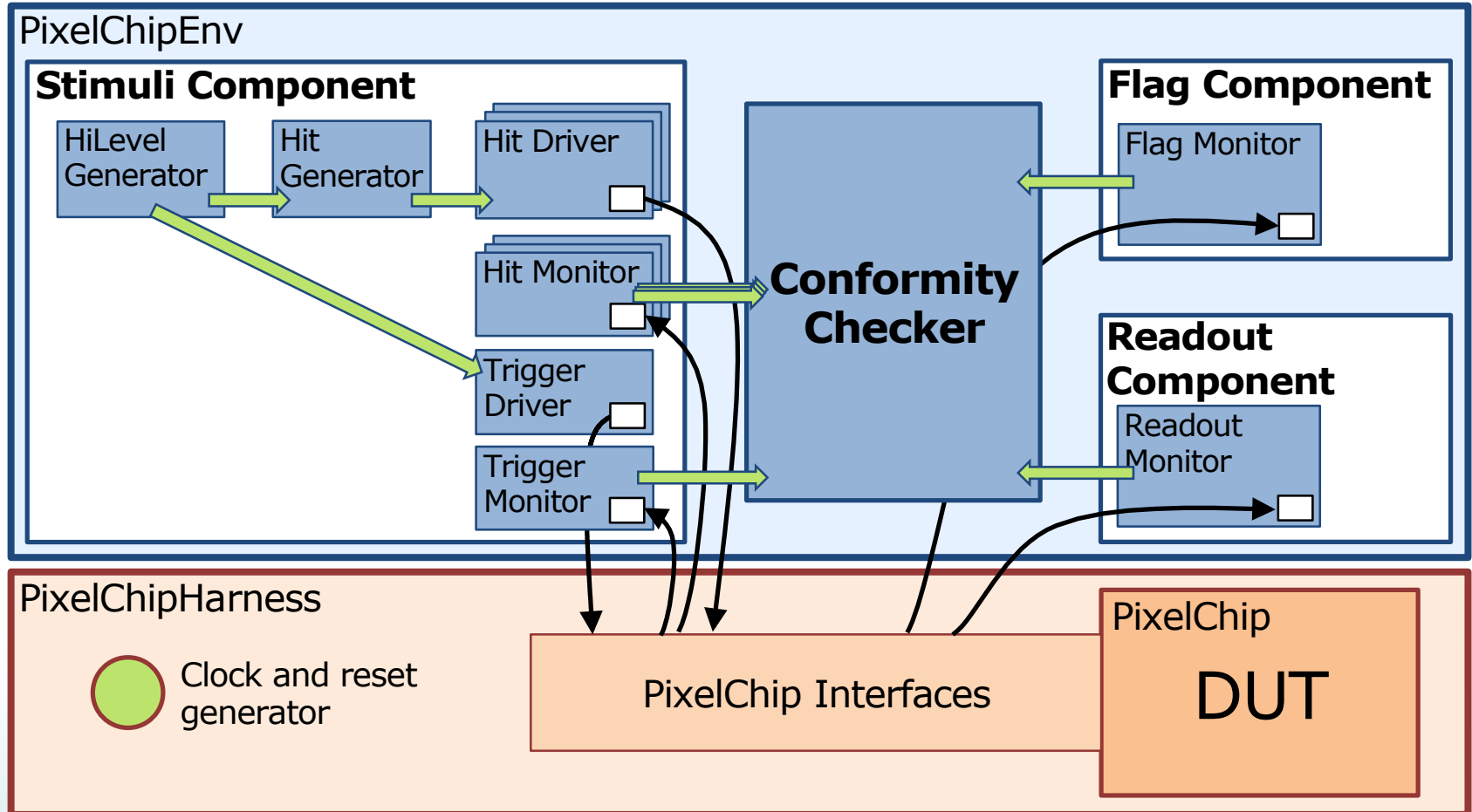
Verilog
elements
(M) library

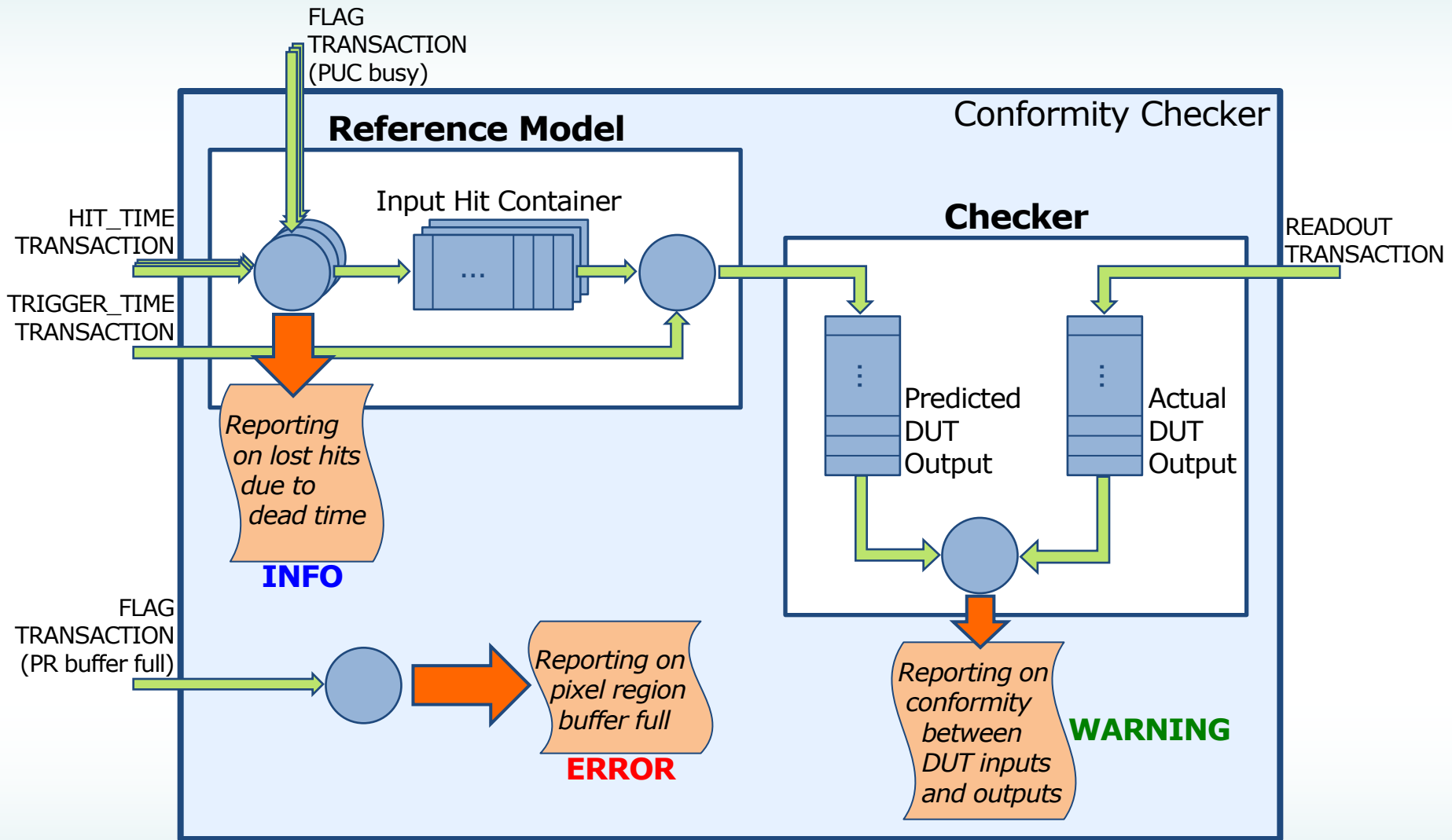
Current version of DUT contains a single pixel region with a custom number of pixels



Class-based SystemVerilog Verification Environment – Block diagram

- Automated stimuli generation: randomized/external file
- No delays/time walk taken into account so far
- Conformity checks between pixel chip inputs and outputs
- Monitoring and reporting on lost hits (pixel dead time/PR buffer full)





Motivation

Standardize into UVM for:

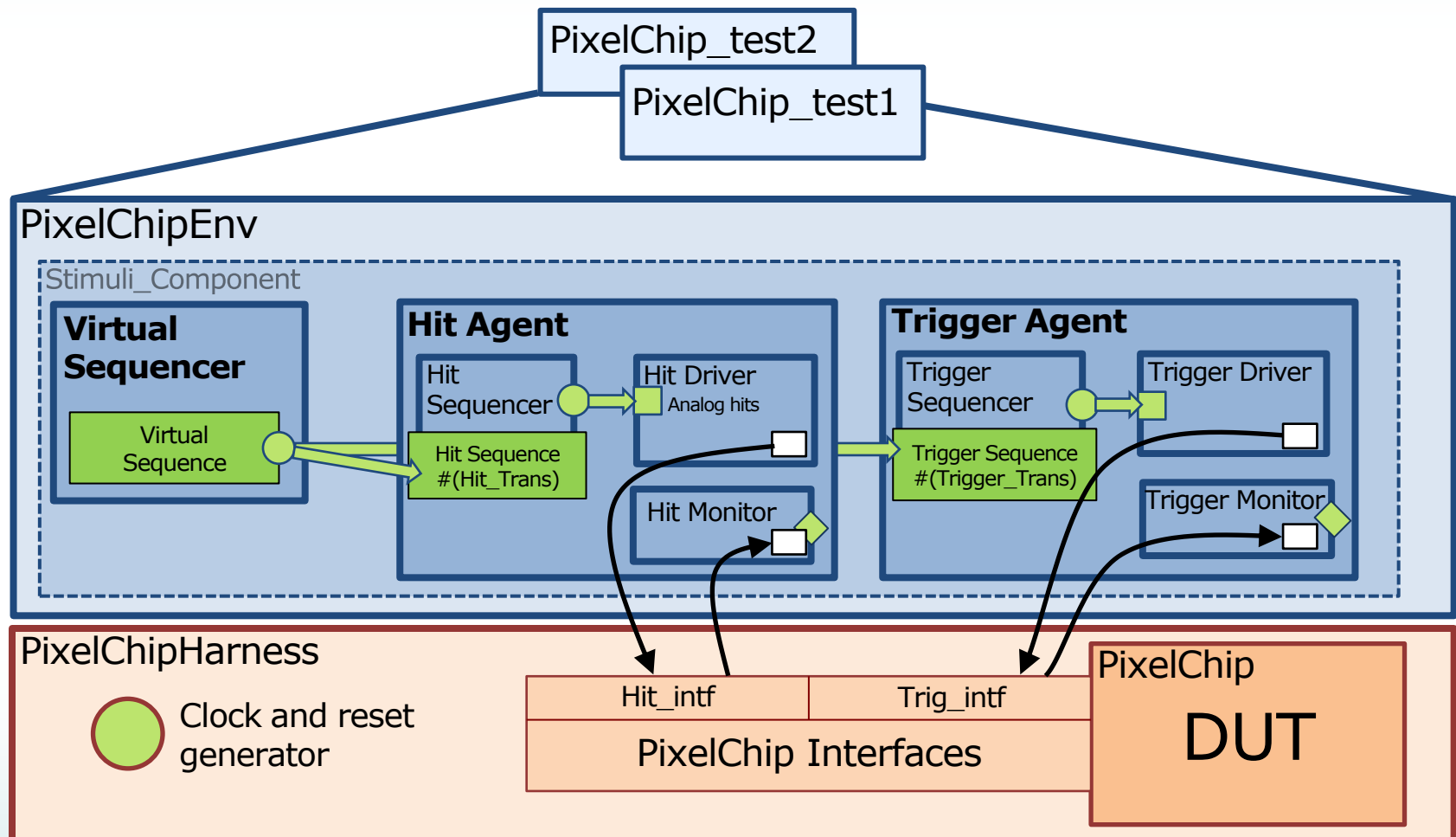
- More solid and documented base classes
- Mature standard and growing community
- Highly customizable reporting features
- Highly configurable and reusable verification environment

At the moment, focus on stimuli generation only

- No Readout/Flag components
- No Conformity Checker
- Study on scalability

UVM Verification Environment – Block Diagram

- One agent is used for each interface of the DUT
- Virtual Sequencer coordinating operations of the agents
- Different tests can be written → configurability



Simulation performance is one of the main issues of the framework:

- Simulations performed with only Stimuli_Component in the PixelChip_Env
 - Matrix size: **1024x256 pixels (256K)**
 - **NO DUT** actually present (*further development needed*)
 - Performance analyzed through **Incisive Advanced Profiler (Iprof)**:
 - **100 transactions** sent in sequence (**to each pixel**):
 - Memory Usage: 20.3M program + 1113.1M data + 1.0M profile = 1134.4M total
 - CPU Usage: 0.8s system + 142.2s user = **143.0s** total (**~2'30"**) (99.9% CPU)
- Resource usage mainly for randomization
- A high level strategy for generating clusters should be defined
- A **benchmark** has also been carried out in order to compare different simulators that are a reasonable option:
 - a fully developed and specific OVM-Verification Environment and Pixel Chip used (**FEI4 model** provided by ATLAS)
- The tool used assures very good simulation performance

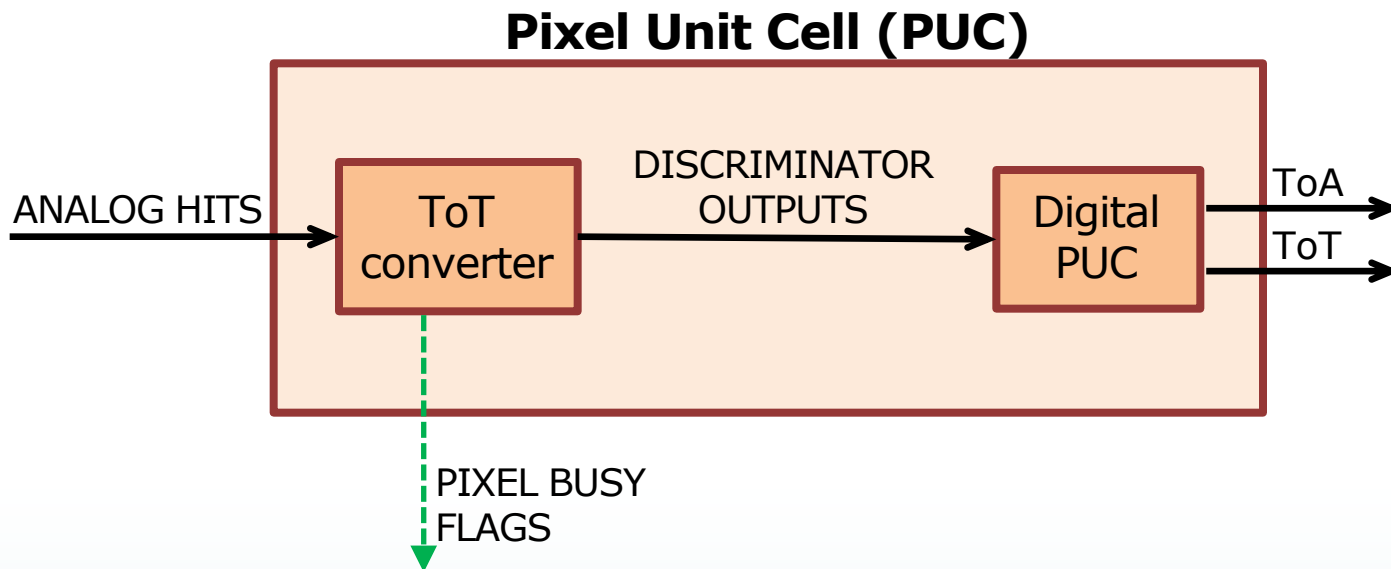
- ✓ Preliminary version of SystemVerilog verification environment
 - Class-based SystemVerilog
 - Standardized into UVM library (focus on stimuli generation only)
- ✓ Study on scalability and simulation performance
 - Simulation performance of the tool used seem to be promising

- Further developments on the DUT:
 - Implement more complex features (i.e. PR columns)
 - Event-based TLM description of pixel chip

- Further developments on the Verification environment:
 - Standardization of other components into UVM
 - Implementation of new components
 - Definition of high level transaction generation strategy

BACKUP

- In order to keep hit generation as general as possible a simple ToT converter module has been defined which abstracts the behavior of the analog front-end
- Current ToT converter does not produce time-walked hits



Stimuli_Component

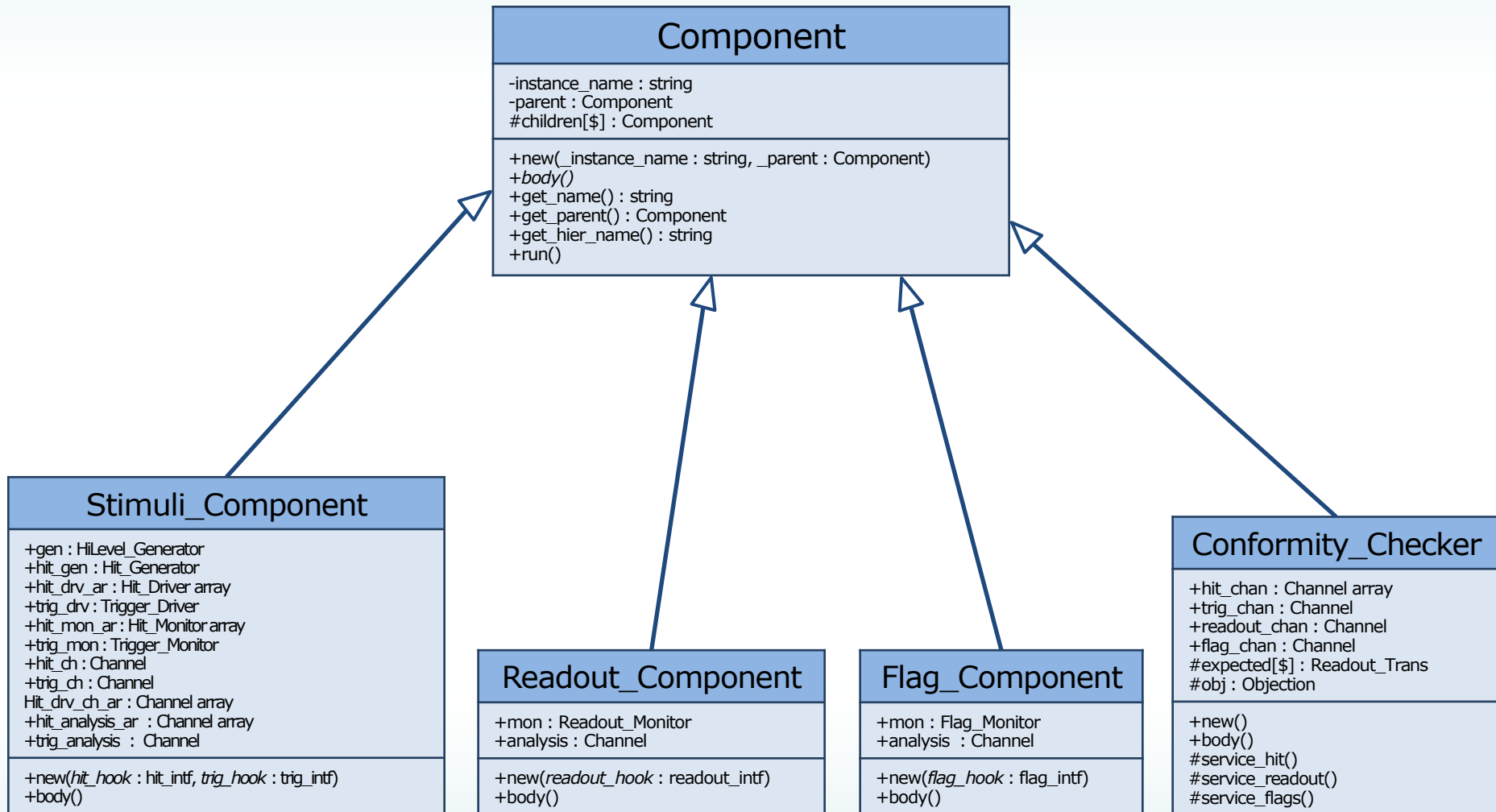
- HiLevel_Generator: generation of high level transactions (randomized or from external file)
- High level transactions are fed to Trigger_Driver (translation into trigger signal) and to Hit_Generator
- Hit_Generator: translation + randomization of high level transactions into a matrix of hit transactions (one Hit_Driver per pixel)
- Hit_Driver: translation into “analog hit” signal
- Hit_Monitor and Trigger_Monitor: generation of hit transactions and trigger transactions (adding time information) from pixel chip inputs

Readout_Component

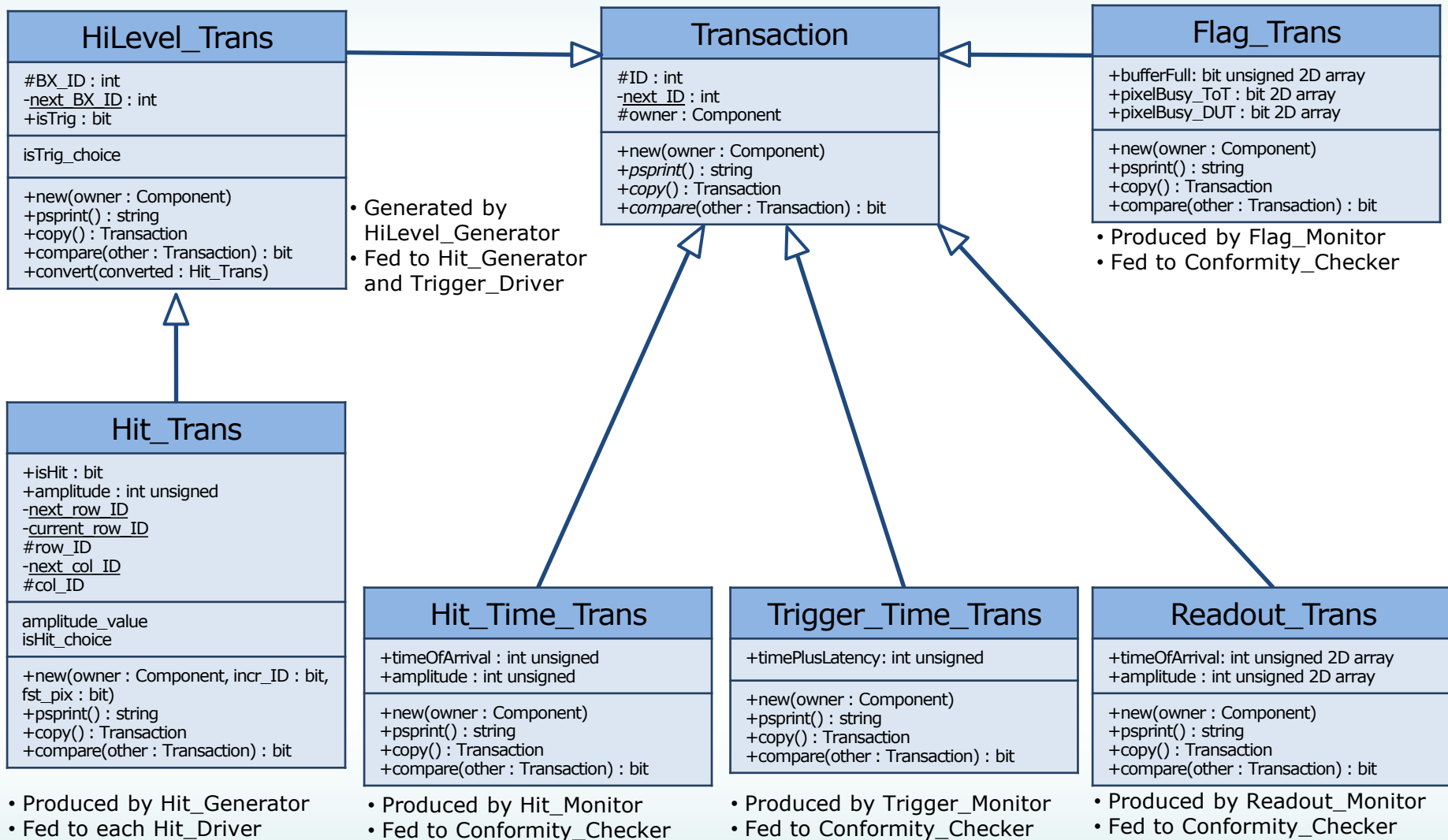
- Readout_Monitor: generation of readout transactions from pixel chip outputs

Flag_Component

- Flag_Monitor: generation of flag transactions from pixel chip flags (pixel busy and PR buffer full)



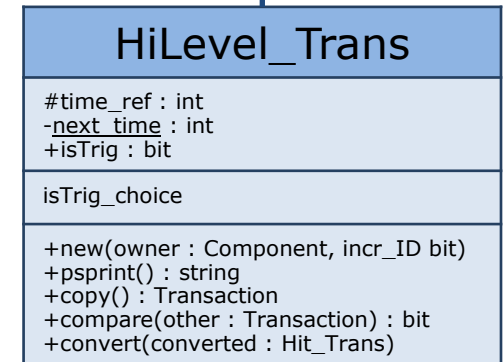
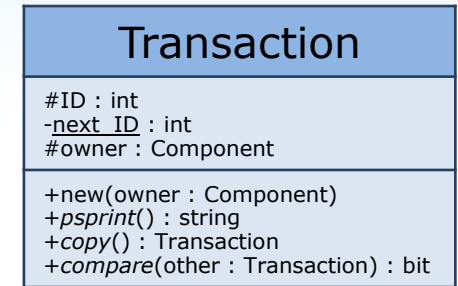
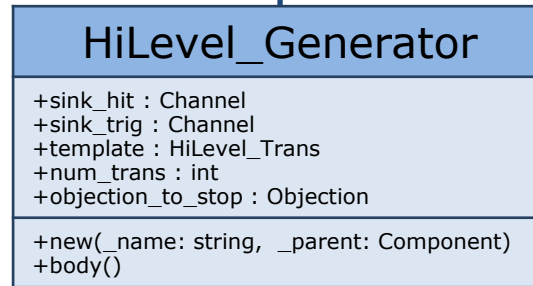
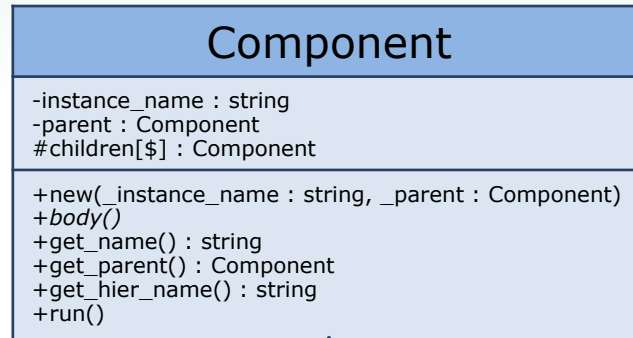
Class-based SystemVerilog Verification Environment – Transactions



Class-based SystemVerilog VE – HiLevel Gen.

HiLevel_Generator
abstracts high level
interaction generator

- For each collision cycle it generates a HiLevel_Trans transaction: any number of transactions can be chosen
- This information is sent to both Hit_Driver and Trigger_Driver on 2 separate channels



Data members of HiLevel_Trans:

- time_ref associated to each transaction (data type: int)
- isTrig (yes/no signal: do we want Trigger_Driver to associate a trigger to current BX?)

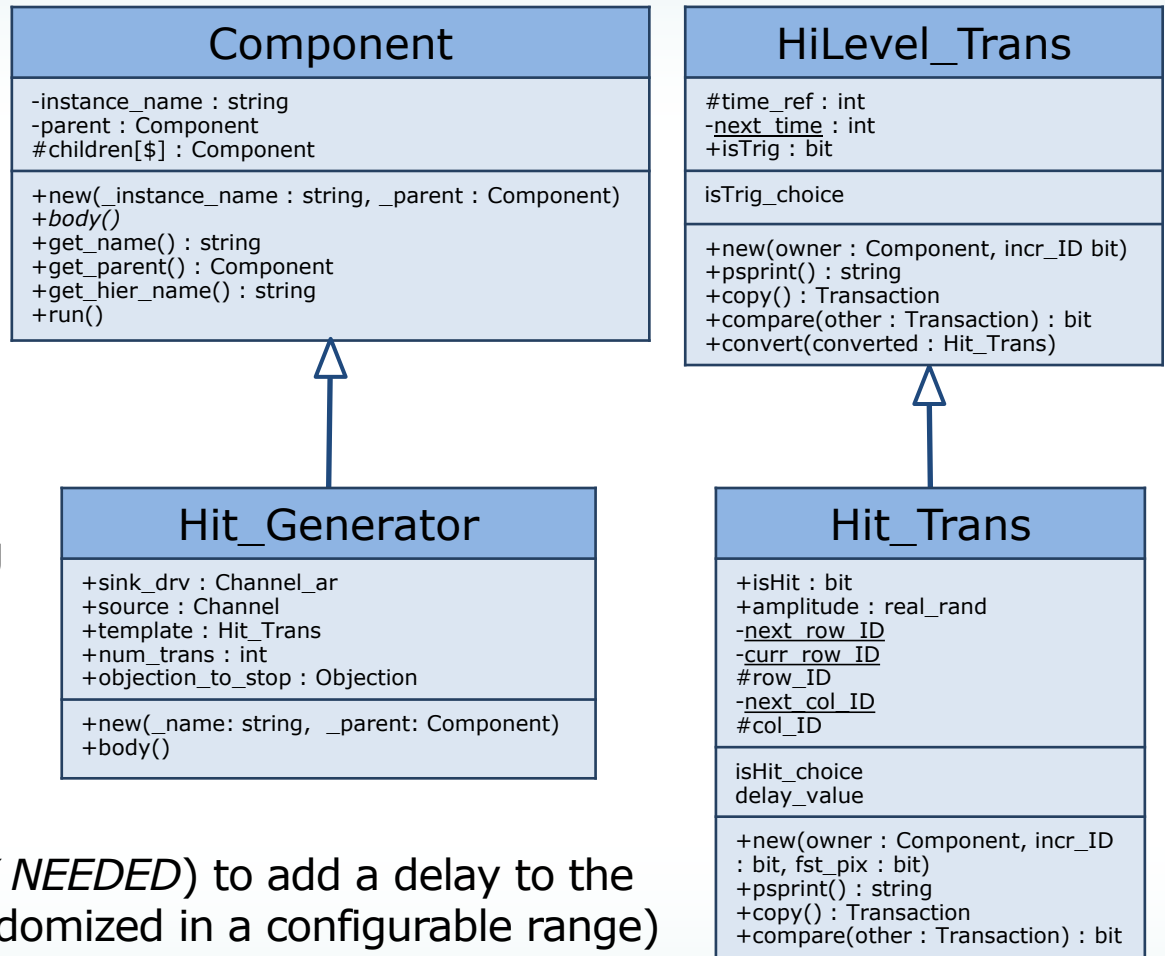
isTrig is randomized at each collision cycle with constraints (50% yes-no probability)

Class-based SystemVerilog VE – Hit Generator

Hit_Generator takes HiLevel_Trans transactions from input channel and translates them in MxN Hit_Trans transactions to be sent through MxN channels to the same number of Hit_Drivers

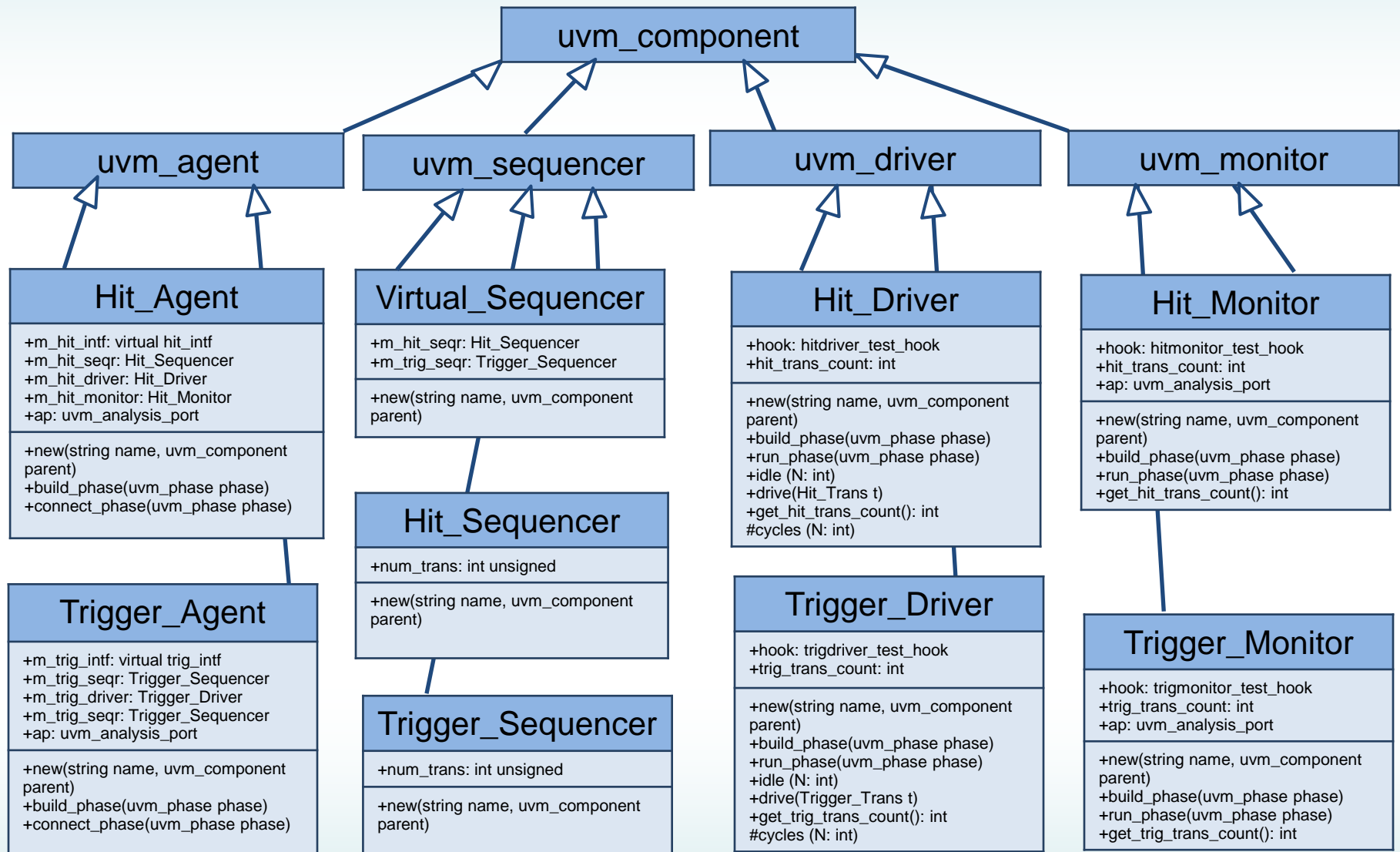
Hit_Trans adds

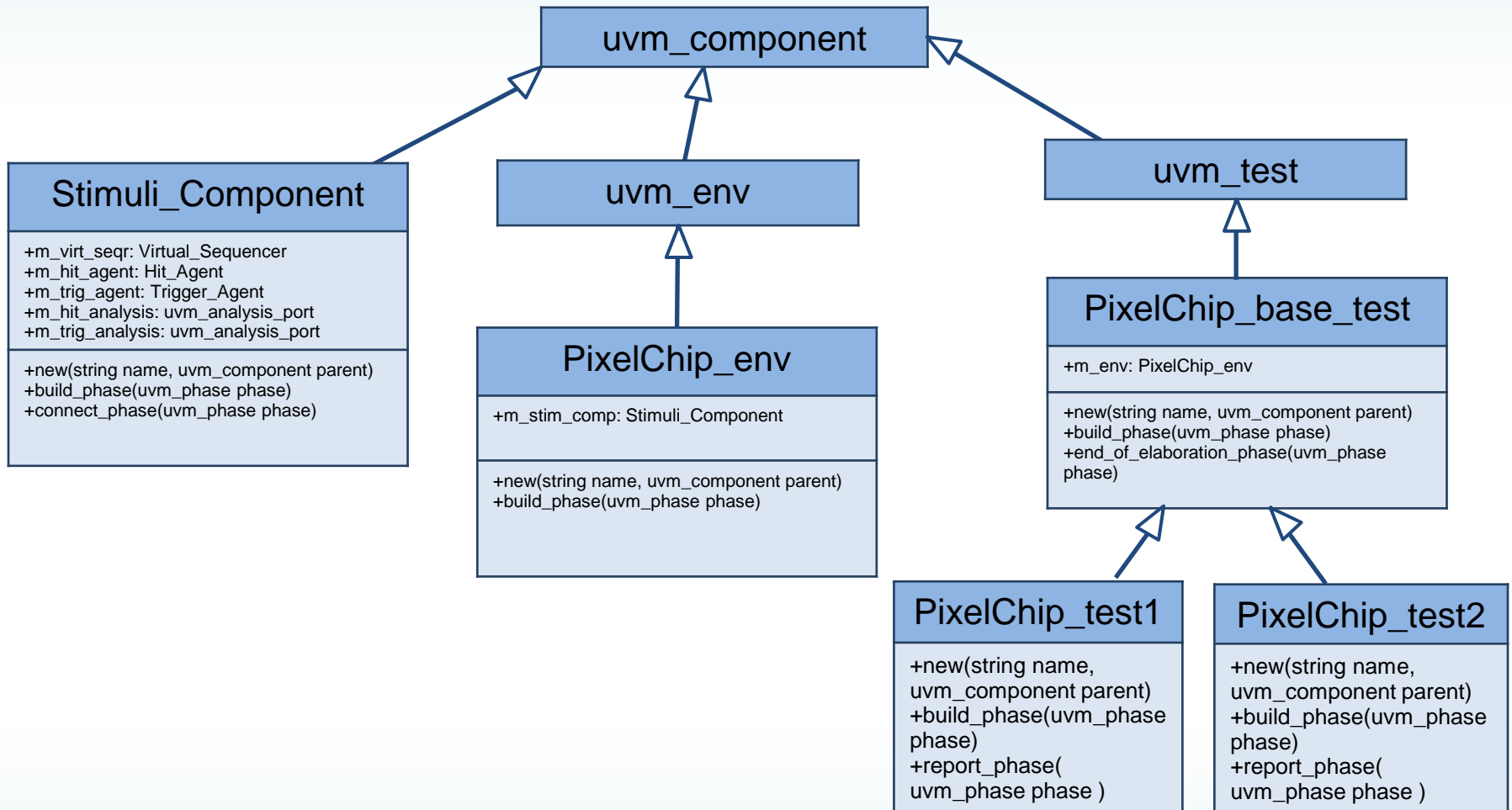
- 2 position indexes according to destination Hit_Driver's
- isHit (yes/no signal: do we want that pixel to be hit during the current BX)?
- Hit amplitude
- Hit_delay (*FURTHER STUDY NEEDED*) to add a delay to the hit generation (could be randomized in a configurable range)

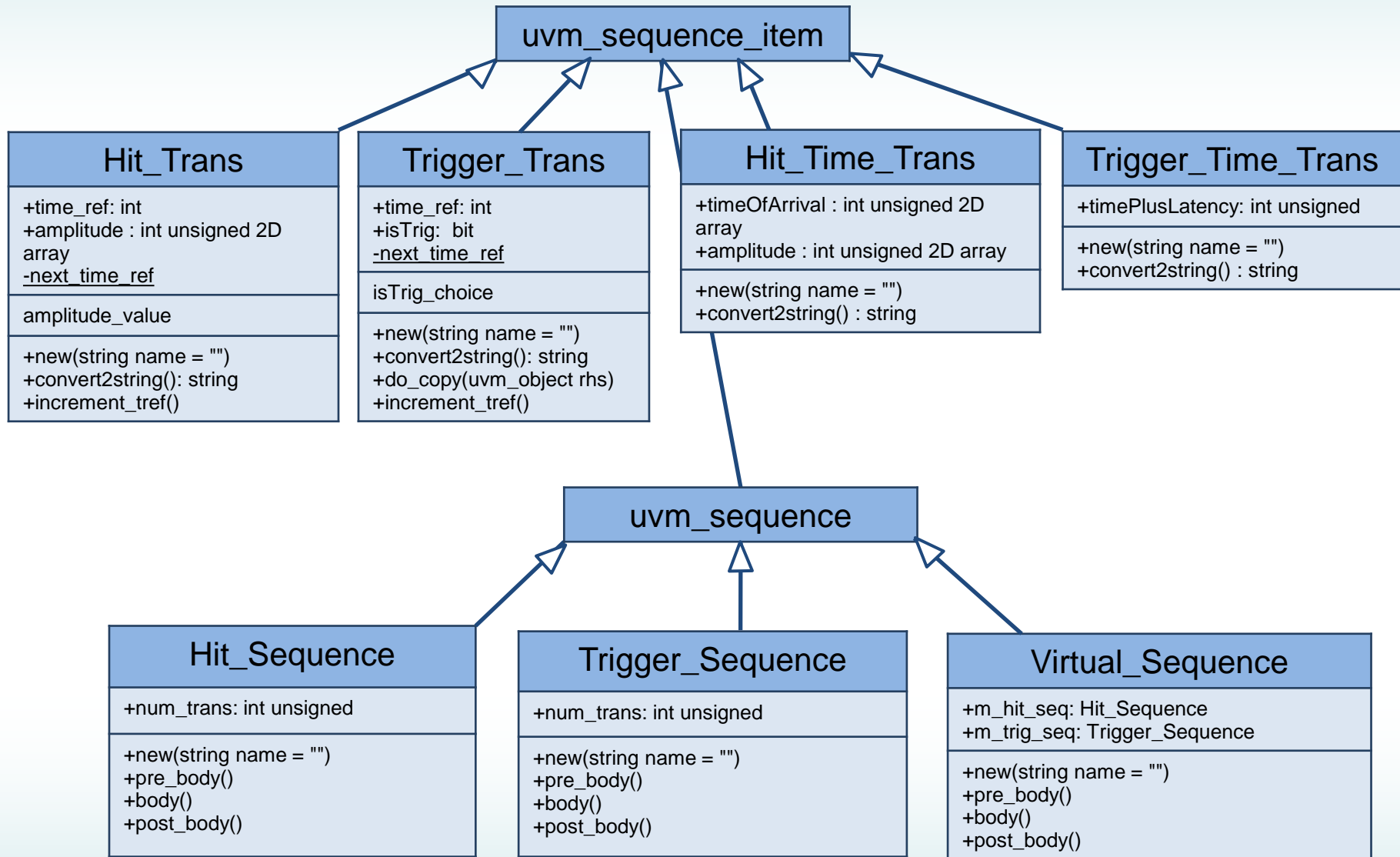


So far, amplitude, isHit are randomized at each collision cycle for each channel with constraints (amplitude in a given range, isHit with 50% yes-no probability)

CMS pixel phase 2 electronics meeting – 20/11/2013







Agents

- Single Hit Agent with transaction containing 2D array of hits
- Trigger Agent is responsible for the trigger generation

Sequences and sequencers

- Hit_Sequence: generates a user-defined number of Hit_Trans
- Trigger_Sequence: generates a user-defined number of Trigger_Trans
- Virtual_Sequence: higher level sequence that coordinates lower level ones
- One sequencer per each sequence

Test

- Automatically instantiated when launched by top-level module
- Specified through command line
- Configures the environment (override classes, active/passive agents, number of transactions, default sequences to be run...) before building it
 - VE source code does not need to be altered, only accessing the test file one can customize the test
- Different tests are being defined

- Simulation performance is one of the main issues of the framework
- A study has been carried out in order to compare different simulators that are a reasonable option:
 - Vendor A
 - Vendor B
- In order to obtain meaningful results, a fully developed and specific OVM-Verification Environment and Pixel Chip has been used (**FEI4_B provided by ATLAS**)
- Both gate level and RTL model have been used for the DUT
- Different philosophy between tools when dealing with optimization:
 - **Vendor A:** Optimization options have to be indicated in the simulation command, otherwise no optimization is performed
 - **Vendor B:** if not differently specified, optimization is automatically performed (and access to the design is restricted)

- The comparison has been done on the time spent by the simulator in:
 1. Compilation of libraries
 2. Elaboration of the design hierarchy
 3. Actual Simulation

- 1. The two tools have shown that compilation of libraries is not a bottleneck
- 2. An important difference has instead been observed in terms of elaboration time:
 - Vendor A: much faster
 - Vendor B: an approach that separates the elaboration of the DUT and of the Verification Environment can be used to overcome this bottleneck (when dealing with verification)
- 3. Remarkable difference observed in terms of simulation time:
 - Vendor B: simulations are 3-6X faster